

# **Notice of References Cited**

Application/Control No.

09/911,033

Applicant(s)/Patent Under  
Reexamination  
LACKRITZ ET AL.

Examiner

Kaj Olsen

Art Unit

1753

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	C	US-6,010,608	01-2000	Ramsey, J. Michael	204/453
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	N	WO 98/27423	06-1998	WIPO	Buchmeiser et al.	
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## **NON-PATENT DOCUMENTS**

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	U	Kameoka et al, Analytical Chemistry, 73(9), pp. 1935-1941, 2001.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.